ON Semiconductor

Is Now

To learn more about onsemi™, please visit our website at
www.onsemi.com

MOSFET - Power, Single N-Channel, μ8FL

100 V, 30 mΩ, 35 A

NTTFS030N10G

ON Semiconductor®

www.onsemi.com

Features

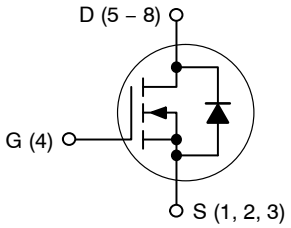
- Wide SOA for Linear Mode Operation
- Low $R_{DS(on)}$ to Minimize Conduction Losses
- High Peak UIS Current Capability for Ruggedness
- Small Footprint (3.3 x 3.3 mm) for Compact Design
- These Devices are Pb−Free, Halogen Free/BFR Free and are RoHS Compliant

Typical Applications

- 48 V Hot Swap System, Load Switch, Soft−Start, E−Fuse

$V_{(BR)DSS}$	$R_{DS(on)}$ MAX	I_D MAX
100 V	30 mΩ @ 10 V	35 A

N−Channel



MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

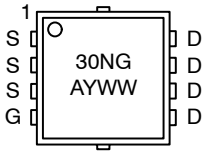
Parameter			Symbol	Value	Unit
Drain−to−Source Voltage			V_{DSS}	100	V
Gate−to−Source Voltage			V_{GS}	±20	V
Continuous Drain Current $R_{\theta JC}$ (Note 2)	Steady State	T_C = 25°C	I_D	35	A
		T_C = 100°C		24	
Power Dissipation $R_{\theta JC}$ (Note 2)		T_C = 25°C	P_D	74	W
		T_C = 100°C		37	
Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2)	Steady State	T_A = 25°C	I_D	6	A
		T_A = 100°C		4	
Power Dissipation $R_{\theta JA}$ (Notes 1, 2)		T_A = 25°C	P_D	2.5	W
		T_A = 100°C		1.2	
Pulsed Drain Current	T_A = 25°C, t_p = 10 μs		I_{DM}	306	A
Operating Junction and Storage Temperature Range			T_J, T_{stg}	−55 to +175	°C
Source Current (Body Diode)			I_S	61	A
Single Pulse Drain−to−Source Avalanche Energy ($I_{L(pk)}$ = 13 A, L = 1 mH)			E_{AS}	84	mJ
Lead Temperature Soldering Reflow for Soldering Purposes (1/8″ from case for 10 s)			T_L	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Surface−mounted on FR4 board using a 1 in^2, 1 oz. Cu pad.
2. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

WDFN8
(μ8FL)
CASE 511DY

MARKING DIAGRAM



30NG = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week

ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Value	Unit
Junction−to−Case − Steady State (Note 2)	$R_{\theta JC}$	2.0	°C/W
Junction−to−Ambient − Steady State (Note 2)	$R_{\theta JA}$	60	

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Typ	Max	Unit
OFF CHARACTERISTICS							
Drain−to−Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} = 0 V, I_D = 250 μA		100			V
Drain−to−Source Breakdown Voltage Temperature Coefficient	$V_{(BR)DSS}/T_J$	I_D = 250 μA, referenced to 25°C			90.8		mV/°C
Zero Gate Voltage Drain Current	I_{DSS}	V_{GS} = 0 V, V_{DS} = 80 V	T_J = 25°C			1	μA
			T_J = 150°C			100	
Gate−to−Source Leakage Current	I_{GSS}	V_{DS} = 0 V, V_{GS} = ±20 V				±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	$V_{GS(TH)}$	V_{GS} = V_{DS}, I_D = 61 μA		2.0		4.0	V
Negative Treshold Temperature Coefficient	$V_{GS(TH)}/T_J$	I_D = 61 μA, referenced to 25°C			−9.5		mV/°C
Drain−to−Source On Resistance	$R_{DS(on)}$	V_{GS} = 10 V, I_D = 12 A			23	30	mΩ
Forward Transconductance	g_{FS}	V_{DS} = 5 V, I_D = 12 A			3.8		S
Gate−Resistance	R_G	T_A = 25°C			0.7		Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C_{iss}	V_{GS} = 0 V, f = 1 MHz, V_{DS} = 50 V			1366		pF
Output Capacitance	C_{oss}				161		
Reverse Transfer Capacitance	C_{rss}				21.5		
Total Gate Charge	$Q_{G(TOT)}$	V_{GS} = 10 V, V_{DS} = 50 V, I_D = 12 A			21.5		nC
Threshold Gate Charge	$Q_{G(TH)}$				4		
Gate−to−Source Charge	Q_{GS}				8.4		
Gate−to−Drain Charge	Q_{GD}				4.7		
Output Charge	Q_{OSS}	V_{GS} = 10 V, V_{DS} = 50 V			15.6		
SWITCHING CHARACTERISTICS (Note 4)							
Turn−On Delay Time	$t_{d(on)}$	V_{GS} = 10 V, V_{DS} = 50 V, I_D = 12 A, R_G = 4.7 Ω			13.4		ns
Rise Time	t_r				5.1		
Turn−Off Delay Time	$t_{d(off)}$				19		
Fall Time	t_f				4.3		
DRAIN−SOURCE DIODE CHARACTERISTICS							
Forward Diode Voltage	V_{SD}	V_{GS} = 0 V, I_S = 12 A	T_J = 25°C		0.84	1.2	V
			T_J = 125°C		0.71		
Reverse Recovery Time	t_{RR}	V_{GS} = 0 V, dI_S/dt = 300 A/μs, I_S = 6 A			25.7		ns
Reverse Recovery Charge	Q_{RR}				80.8		nC
Reverse Recovery Time	t_{RR}	V_{GS} = 0 V, dI_S/dt = 1000 A/μs, I_S = 6 A			22.2		ns
Reverse Recovery Charge	Q_{RR}				156		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
4. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

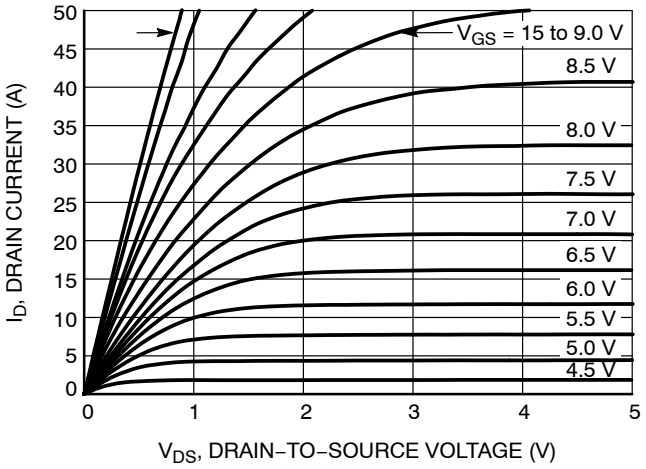


Figure 1. On−Region Characteristics

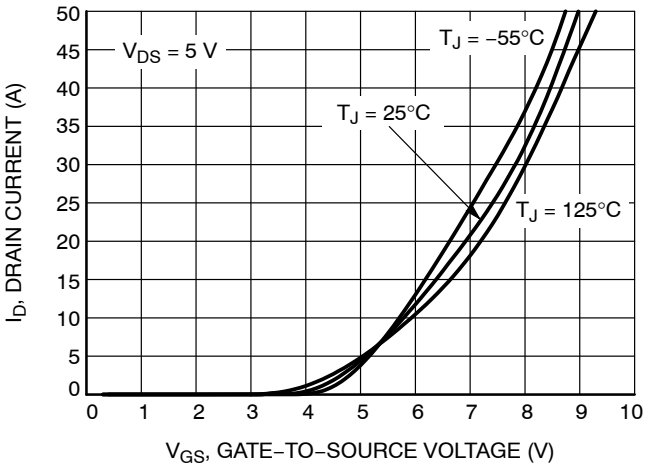


Figure 2. Transfer Characteristics

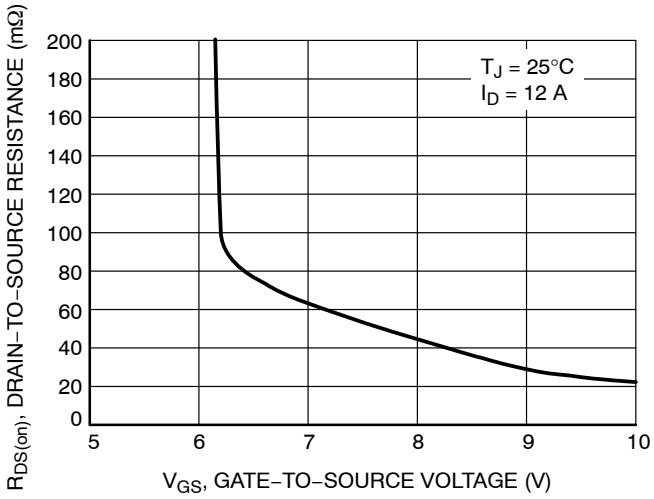


Figure 3. On−Resistance vs. Gate−to−Source Voltage

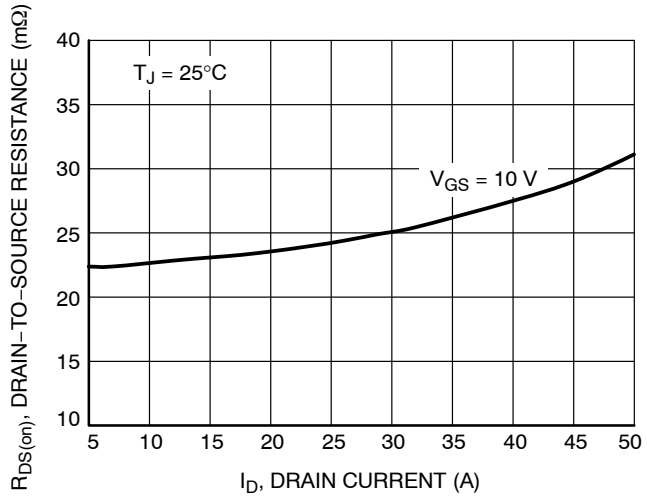


Figure 4. On−Resistance vs. Drain Current

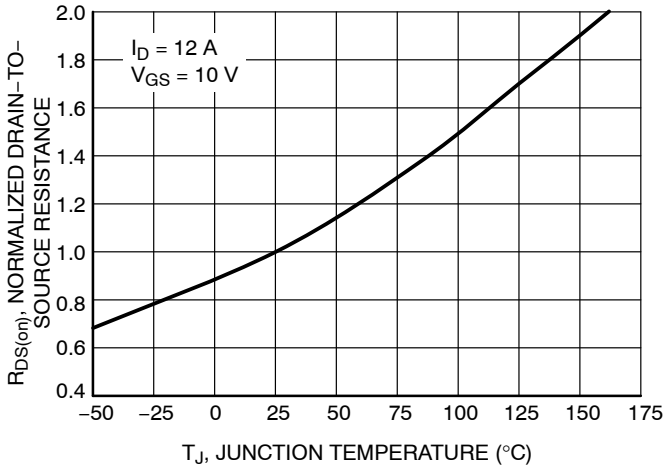


Figure 5. On−Resistance Variation with Temperature

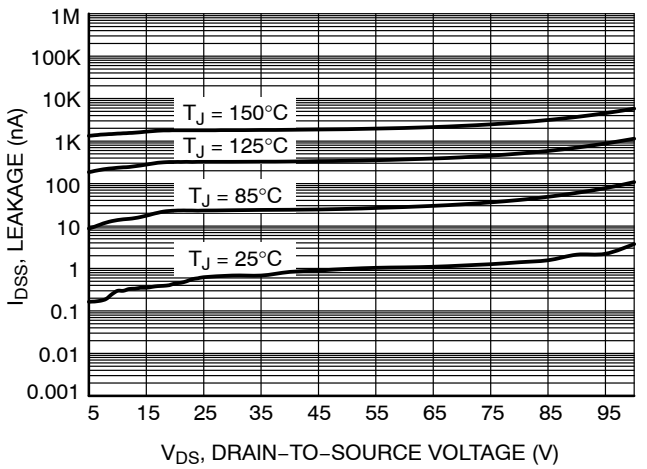


Figure 6. Drain−to−Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

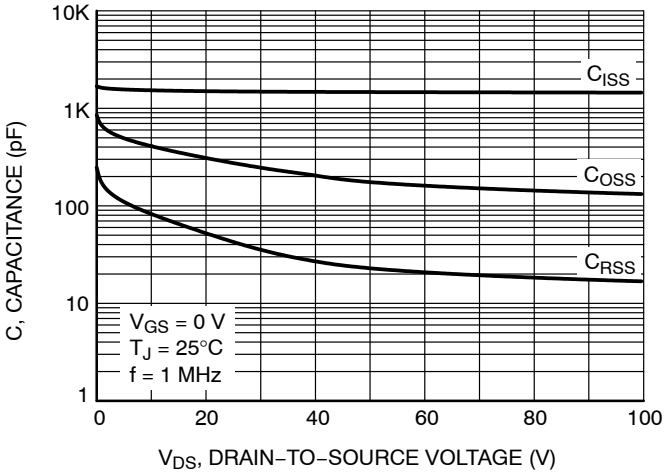


Figure 7. Capacitance Variation

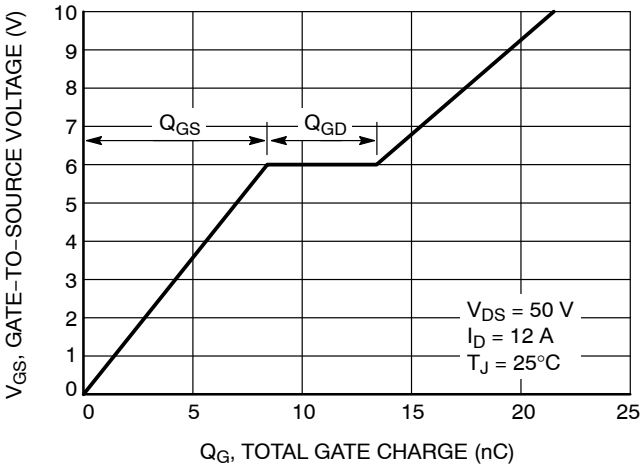


Figure 8. Gate−to−Source Voltage vs. Total Charge

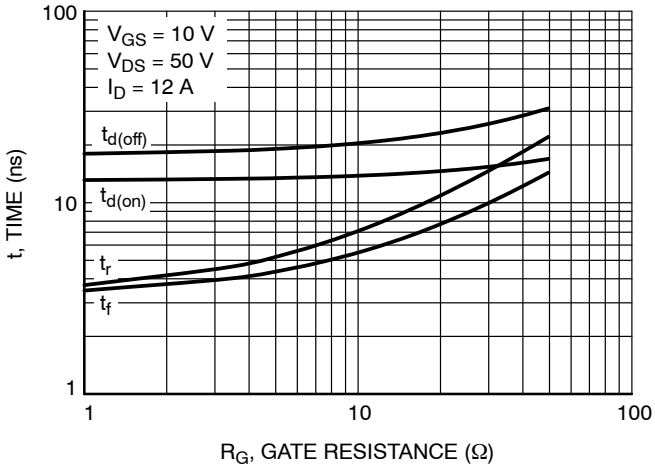


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

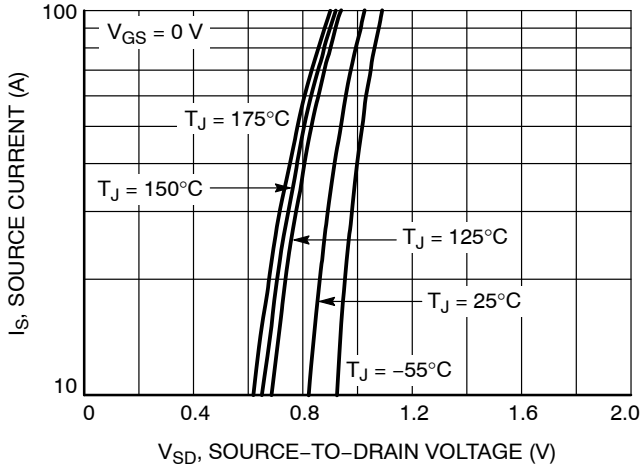


Figure 10. Diode Forward Voltage vs. Current

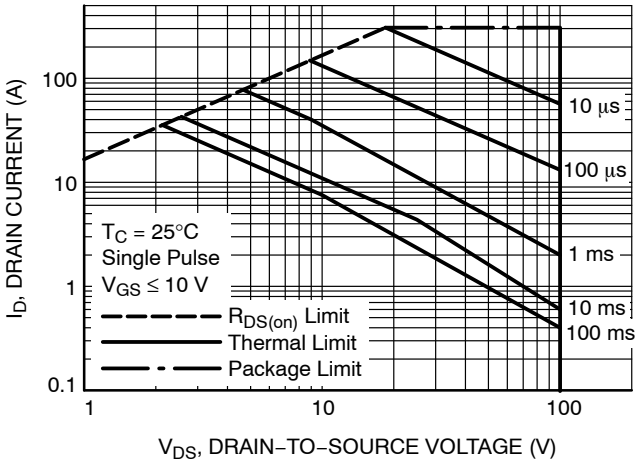


Figure 11. Maximum Rated Forward Biased Safe Operating Area

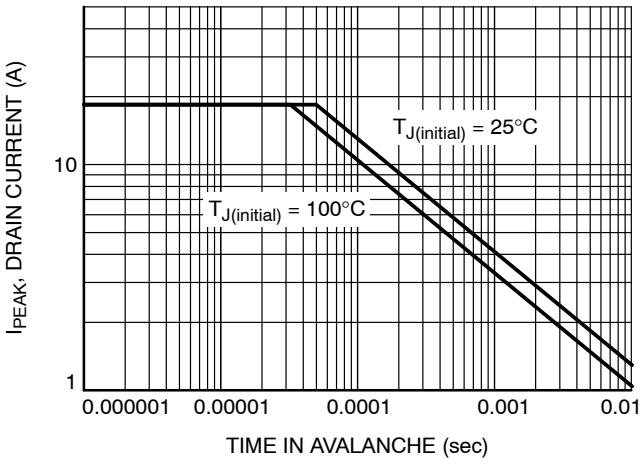


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS

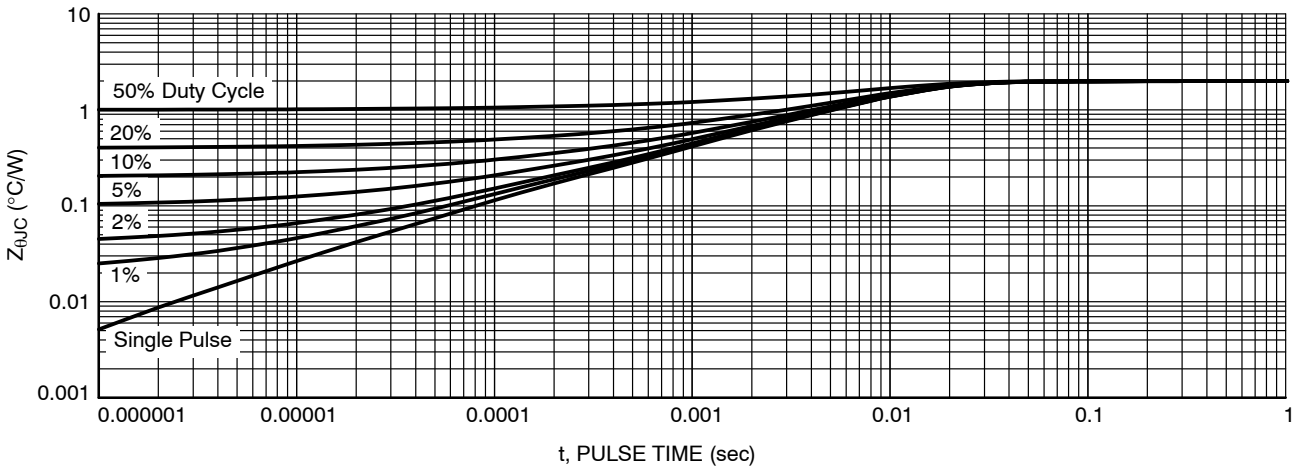


Figure 13. Junction−to−Ambient Transient Thermal Response

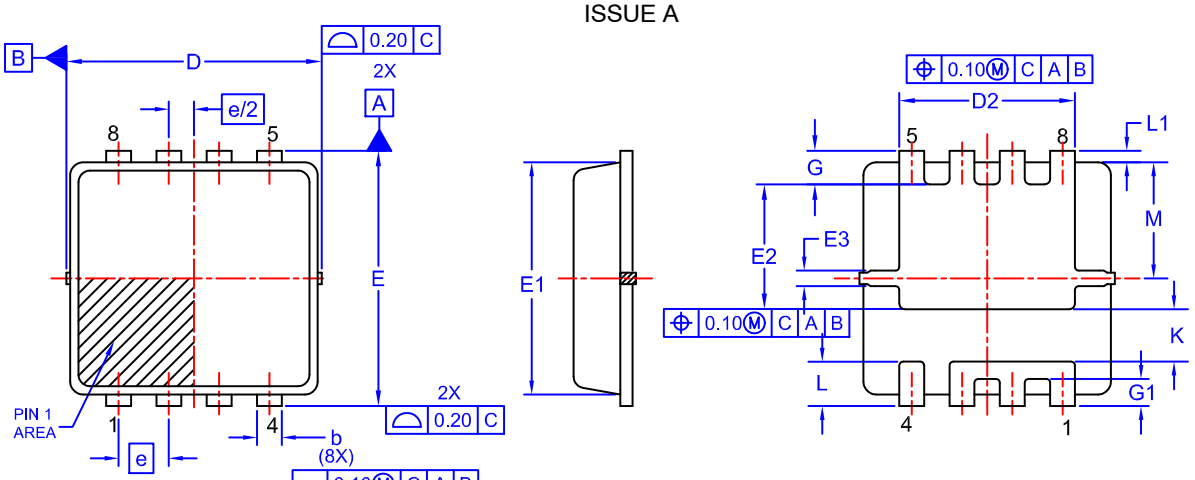
DEVICE ORDERING INFORMATION

Device	Marking	Package	Shipping†
NTTFS030N10G	30NG	μ8FL (Pb−Free)	1500 / Tape & Reel

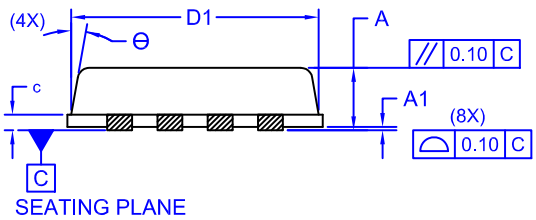
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

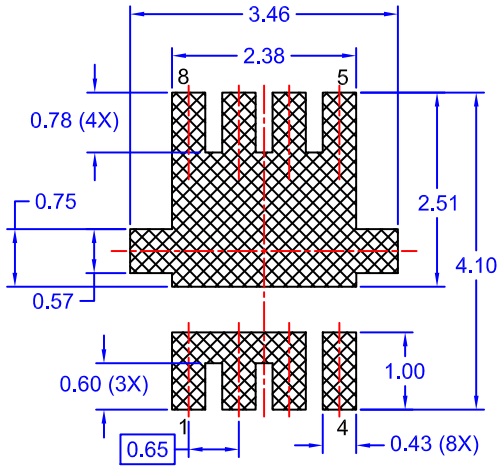
WDFN8 3.3x3.3, 0.65P
CASE 511DY
ISSUE A



NOTES:
1. CONTROLLING DIMENSION: MILLIMETERS
2. DIMENSIONS D1 & E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS.



DIM	MILLIMETERS		
	MIN	NOM	MAX
A	0.70	0.75	0.80
A1	0.00	-	0.05
b	0.23	0.33	0.43
c	0.15	0.20	0.25
D	3.20	3.30	3.40
D1	2.95	3.13	3.30
D2	1.98	2.20	2.40
E	3.20	3.30	3.40
E1	2.80	3.00	3.15
E2	1.40	1.60	1.80
E3	0.15	0.25	0.40
e	0.65 BSC		
G	0.30	0.43	0.55
G1	0.25	0.35	0.45
K	0.55	0.75	0.95
L	0.35	0.52	0.65
L1	0.06	0.15	0.30
M	1.35	1.50	1.60
Θ	0	-	12



RECOMMENDED LAND PATTERN

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT
North American Technical Support:
Voice Mail: 1 800−282−9855 Toll Free USA/Canada
Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:
Phone: 00421 33 790 2910
For additional information, please contact your local Sales Representative

◊